

Notice of References Cited	Application/Control No. 09/608,886	Applicant(s)/Patent Under Reexamination SELINFREUND ET AL.	
	Examiner Martin J Angebranndt	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,638,593 B2	10-2003	Selinfreund et al.	428/64.1
	B	US-6,589,626 B2	07-2003	Selinfreund et al.	428/64.1
	C	US-4,090,031 A	05-1978	Russell	365/127
	D	US-5,526,329 A	06-1996	Bish et al.	369/124.11
	E	US-5,213,955 A	05-1993	Hamada et al.	369/284
	F	US-5,204,852 A	04-1993	Nakagawa et al.	369/275.1
	G	US-5,930,217 A	07-1999	Kayanuma, Kanji	369/59.25
	H	US-5,388,085 A	02-1995	Jaquette, Glen A.	369/30.12
	I	US-5,132,954 A	07-1992	Kulakowski et al.	369/47.12
	J	US-6,580,680 B1	06-2003	Van Den Enden et al.	369/275.3
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Skoog et al., "Principles of Instrumental Analysis", (1980) pp. 282-284,307.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.